

# 15th IEEE Latin-American Test Workshop – LATW'14

Gran Marquise Hotel, Fortaleza, Brazil  
March 12 - 15, 2014

## BELAS Registration Form

### 2<sup>nd</sup> Biannual European - Latin American Summer School on Design, Test and Reliability Gran Marquise Hotel, Fortaleza, March 10-11, 2014

The IEEE Latin American Test Workshop (LATW'14) will be held in the city of Fortaleza (Brazil) from 12<sup>th</sup> to 15<sup>th</sup> March 2014. To celebrate its 15<sup>th</sup> anniversary, LATW'14 is hosting the 2<sup>nd</sup> Biannual European - Latin American Summer School on Design, Test and Reliability (BELAS'14). BELAS provides training in these three crucial areas of electronic circuits and systems. The series of BELAS events is organized twice a year during the summers in the Northern and Southern Hemispheres. The 1<sup>st</sup> BELAS took place in Tallinn, Estonia, on June 19-21, 2013. Distinguished experts from Latin America and Europe will share their knowledge with Latin American and European PhD, MSc students and Post-Docs. Participation fee is free of charge. In addition to attend the courses, participants are also invited to present their research at the [PhD & MSc Forum](#), to take place during LATW.

#### March 10th:

**09:00:** Opening Address - Fabian Vargas (PUCRS, Brazil), Maksim Jenihhin (TUT, Estonia), Letícia Bolzani Poehls (PUCRS, Brazil)

"Design Error Debug is Fun if You Have the Right Tool for the Job"  
*Maksim Jenihhin, Tallinn University of Technology – TUT, Estonia and Jaan Raik, Tallinn University of Technology – TUT, Estonia*

**11:30:** Lunch

**13:30:** "Ionizing Radiation Effects on Integrated Circuits and Test Procedures"  
*Jose Lipovetzky, Universidad de Buenos Aires – UBA, Argentina*

Coffee-Break

"3D Stacked ICs: Yield Improvement, Design for Testability, and Test Cost Optimization"  
*Said Hamdioui, Delft University of Technology, Netherlands*

#### March 11th:

**09:30:** "Software Development, Debugging and Verification on a Virtual Prototype"  
*Djones Lettnin, Federal University of Santa Catarina – UFSC, Brazil and Markus Winterholer, Cadence Design Systems, Inc., Germany*

**11:30:** Lunch

**13:30:** "Design of On-Chip Sensors to Monitor Electromagnetic Activity in ICs: Towards On-line Diagnosis and Self-Healing"  
*Sonia Ben Dhia, LAAS-INSA/Toulouse, France*

Coffee-Break

"Regaining Hardware Trust: Adoption of Test Principles"  
*Ozgur Sinanoglu, New York University Abu Dhabi, United Arab Emirates and Ramesh Karri, Polytechnic Institute of New York University, USA*

Closing Remarks - Fabian Vargas (PUCRS, Brazil)